

具有总线唤醒功能的低功率网络控制器局域网络 (CAN) 收发器

查询样品: [SN65HVD1040-HT](#)

特性

- 改进的针对 **TJA1040** 的简易替换器件
- **±12 kV** 静电放电 (ESD) 保护
- 具有总线唤醒功能的低电流待机模式: 典型值 **5 μ A**
- **-27 V** 至 **40 V** 的总线故障保护
- 耐用的拆分式引脚总线稳定性
- 主计时功能
- 热关断已被移除
- 加电/断电无毛刺脉冲总线输入和输出
 - 具有低 **V_{CC}** 的高输入阻抗
 - 电源循环期间单片输出
- **DeviceNet** 供应商标识号 (ID) #806

支持极端温度应用

- 受控基线
- 一个组装/测试场所
- 一个制造场所
- 可在 **-55°C/210°C** 的极端温度范围内工作 ⁽¹⁾
- 产品生命周期有所延长
- 拓展的产品变更通知
- 产品可追溯性
- 德州仪器的高温产品运用了高度优化的硅片 (芯片) 解决方案, 此类解决方案在设计与工艺方面均有所强化, 以在扩展的温度范围内实现性能的最大化。在最大额定温度下, 所有器件可连续正常运行 **1000** 小时。

应用范围

- 潜孔钻进
- 高温环境
- 振动/模式分析
- 多通道数据采集
- 声学/动态应变仪
- 压力传感器

(1) 可定制工作温度范围

说明

SN65HVD1040 满足或者超过 ISO 11898 标准中规定的对于采用控制器局域网络 (CAN) 的应用所要求的技术规范。作为 CAN 收发器, 这些器件能够为信号传输速率高达每秒钟 1 兆比特 (Mbps) 的 CAN 控制器提供差分传输和接收能力。 ⁽²⁾

被设计运行在恶劣环境下, 此器件在总线和拆分引脚上特有 **±12 kV ESD** 保护, 以及交叉线, 过压保护和 **-27 V** 至 **40 V** 的失地保护, 一个 **-12 V** 至 **12 V** 的共模范围, 并且根据 ISO 7637 标准能承受从 **-200 V** 到 **200 V** 的电压瞬变。

STB 输入 (引脚8) 用于在两个不同的运行模式间做出选择; 即高速模式或者低速模式。通过将 STB 引脚接地来选择高速运行模式。

如果一个高逻辑电平被加在 SN65HVD1040 的 STB 引脚上, 此器件进入一个低功率总线监控待机模式。当 SN65HVD1040 运行在低功率总线监控待机模式下的时候, 总线上一个大于 **5 μ s** 的显性位由总线监控电路传递到接收器输出。然后, 当此器件需要向总线传输数据时, 此本地协议控制器可以重新激活此器件。

SN65HVD1040 内的主计时电路在硬件或者软件故障期间防止此驱动器阻塞网络通信。此计时电路由 TXD (引脚1) 上的下降沿触发。如果在此电路的计时常数过期前没有发现上升沿, 此驱动器将被禁用。此电路被 TXD 上的下一个上升沿复位。

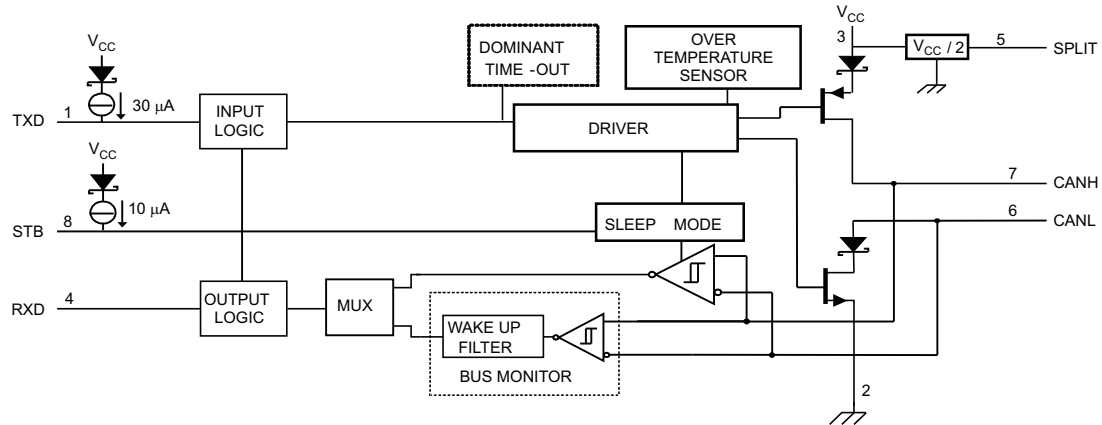
(2) 一条线路的信号传输速率就是电压瞬变的次数, 即每秒钟单位 bps (每秒比特数)。



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

SN65HVD1040 上可具有拆分 (SPLIT) 输出 (引脚 5)，在拆分式终端网络中，此输出可作为一个 $V_{CC}/2$ 共模总线偏置电压。

SN65HVD1040 额定工作温度 -55°C 至 210°C 。





This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

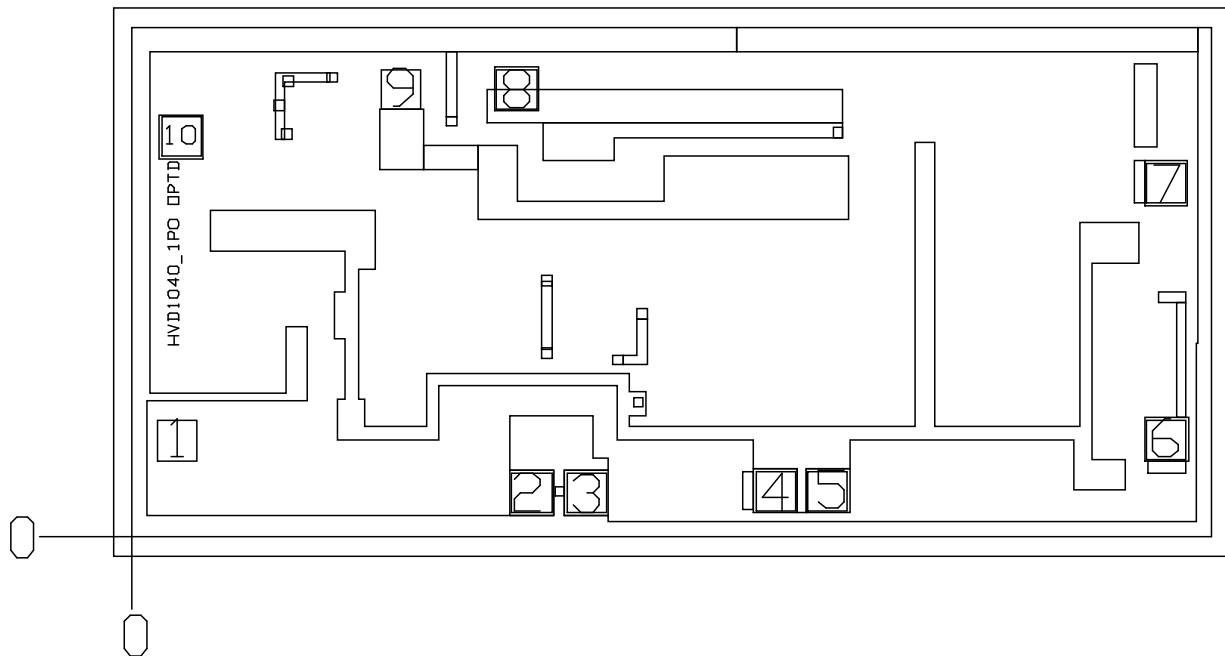
Table 1. ORDERING INFORMATION⁽¹⁾

T _J	PACKAGE	ORDERABLE PART NUMBER	TOP-SIDE MARKING
–55°C to 210°C	KGD (bare die)	SN65HVD1040SKGD3	NA
	HKQ	SN65HVD1040SHKQ	HVD1040SHKQ
–55°C to 175°C	D	SN65HVD1040HD	H1040

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI Web site at www.ti.com.

BARE DIE INFORMATION

DIE THICKNESS	BACKSIDE FINISH	BACKSIDE POTENTIAL	BOND PAD METALLIZATION COMPOSITION	BOND PAD THICKNESS
15 mils.	Silicon with backgrind	Floating	CuNiPd	15 microns


Table 2. BOND PAD COORDINATES (μm)

DESCRIPTION	PAD NUMBER	X MIN	Y MIN	X MAX	Y MAX	PAD SIZE X	PAD SIZE Y
TXD	1	53.64	162	137.7	246.06	84.06	84.06
GND	2	804.06	50.85	888.12	134.91	84.06	84.06
GND	3	920.07	50.85	1004.13	134.91	84.06	84.06
Vcc	4	1320.21	54.18	1404.27	138.24	84.06	84.06
Vcc	5	1431.09	54.18	1515.15	138.24	84.06	84.06
RXD	6	2148.75	164.34	2232.81	248.4	84.06	84.06
SPLIT	7	2147.4	707.49	2231.46	791.55	84.06	84.06
CANL	8	771.93	907.38	855.99	991.44	84.06	84.06
CANH	9	527.31	907.38	611.37	991.44	84.06	84.06
STB	10	62.28	806.13	146.34	890.19	84.06	84.06

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

				VALUE
V _{CC}	Supply voltage ⁽²⁾			−0.3 V to 7 V
V _{I(bus)}	Voltage range at any bus terminal (CANH, CANL, SPLIT)			−27 V to 40 V
I _{O(OUT)}	Receiver output current			-20 mA to 20 mA
Voltage input, transient pulse ⁽³⁾ , (CANH, CANL, SPLIT)				−200 V to 200 V
ESD	IEC Contact Discharge	(IEC 61000-4-2)	Bus terminals vs GND	±6 kV
	Human body model	JEDEC Standard 22, Test Method A114-C.01	Bus terminals vs GND	±12 kV
			All pins	±4 kV
	Field-Induced-Charged Device Model	JEDEC Standard 22, Test Method C101	All pins	±1 kV
	Machine model	ANSI/ESDS5.2-1996		±200 V
IEC			Bus terminals vs GND	±6 kV
V _I	Voltage input range (TXD, STB)			−0.5 V to 6 V
T _J	Junction temperature			−55°C to 210°C

- (1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.
- (3) Tested in accordance with ISO 7637, test pulses 1, 2, 3a, 3b, 5, 6 & 7.

THERMAL CHARACTERISTICS FOR HKQ PACKAGE

over operating free-air temperature range (unless otherwise noted)

PARAMETER			MIN	TYP	MAX	UNIT
θ_{JC}	Junction-to-case thermal resistance	to ceramic side of case			5.7	°C/W
		to top of case lid (metal side of case)			13.7	

THERMAL INFORMATION FOR D PACKAGE

THERMAL METRIC ⁽¹⁾		SN65HVD1040	UNITS
		D	
		8 PINS	
θ_{JA}	Junction-to-ambient thermal resistance ⁽²⁾	91.9	°C/W
θ_{JCTop}	Junction-to-case (top) thermal resistance ⁽³⁾	39.9	
θ_{JB}	Junction-to-board thermal resistance ⁽⁴⁾	40.6	
ψ_{JT}	Junction-to-top characterization parameter ⁽⁵⁾	3.9	
ψ_{JB}	Junction-to-board characterization parameter ⁽⁶⁾	39.6	
θ_{JCbott}	Junction-to-case (bottom) thermal resistance ⁽⁷⁾	N/A	

- (1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, [SPRA953](#).
- (2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
- (3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.
- (4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.
- (5) The junction-to-top characterization parameter, ψ_{JT} , estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA} , using a procedure described in JESD51-2a (sections 6 and 7).
- (6) The junction-to-board characterization parameter, ψ_{JB} , estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA} , using a procedure described in JESD51-2a (sections 6 and 7).
- (7) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

RECOMMENDED OPERATING CONDITIONS

			T _J = -55°C to 125°C			T _J = -55°C to 175°C			T _J = -55°C to 210°C			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC}	Supply voltage		4.75		5.25	4.75		5.25	4.75		5.25	V
V _I or V _{IC}	Voltage at any bus terminal (separately or common mode)		-12 ⁽¹⁾		12	-12 ⁽¹⁾		12	-12 ⁽¹⁾		12	V
V _{IH}	High-level input voltage	TXD, STB	2		5.25	2		5.25	2		5.25	V
V _{IL}	Low-level input voltage		0		0.8	0		0.8	0		0.8	V
V _{ID}	Differential input voltage		-6		6	-6		6	-6		6	V
I _{OH}	High-level output current	Driver	-70			-70			-70			mA
		Receiver	-2			-2			-2			
I _{OL}	Low-level output current	Driver			70			70			70	mA
		Receiver			2			2			2	
t _{SS}	Maximum pulse width to remain in standby				0.7			0.7			0.7	μs
T _J	Junction temperature		-55		125	-55		175	-55		210	°C

(1) The algebraic convention, in which the least positive (most negative) limit is designated as minimum is used in this data sheet.

SUPPLY CURRENT

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	T _J = -55°C to 125°C			T _J = -55°C to 175°C			T _J = -55°C to 210°C			UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
I _{CC}	Supply current, V _{CC}	Dominant V _I = 0 V, 60 Ω Load, STB at 0 V		50	70		50	70		50	70	mA
		Recessive V _I = V _{CC} , STB at 0 V		6	10		6	10		6	10	
		Standby STB at V _{CC} , V _I = V _{CC}		5	12		5	20		5	50	μA

DEVICE SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	T _J = -55°C to 125°C			T _J = -55°C to 175°C			T _J = -55°C to 210°C			UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
t _{loop1}	Total loop delay, driver input to receiver output, Recessive to Dominant	STB at 0 V, See Figure 10	90		230	90		325	90		450	ns
t _{loop2}	Total loop delay, driver input to receiver output, Dominant to Recessive		90		230	90		325	90		450	

DRIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER			T _J = -55°C to 125°C			T _J = -55°C to 175°C			T _J = -55°C to 210°C			UNIT
			MIN	TYP ⁽¹⁾	MAX	MIN	TYP ⁽¹⁾	MAX	MIN	TYP ⁽¹⁾	MAX	
V _{OD} (D)	Bus output voltage (Dominant)	CAN H	2.9	3.4	4.5	2.9	3.4	4.6	2.9	3.4	4.6	V
		CANL	0.8		1.75	0.8		1.75	0.8		1.75	
V _{OD} (R)	Bus output voltage (Recessive)		2	2.5	3	2	2.5	3	2	2.5	3	V
V _O	Bus output voltage (Standby)		-0.1		0.1	-0.125		0.125	-0.15		0.15	V
V _{OD} (D)	Differential output voltage (Dominant)		1.5		3	1.5		3	1.5		3	V
			1.4		3	1.4		3	1.4		3	
V _{SYM}	Output symmetry (Dominant or Recessive) [V _O (CANH) + V _O (CANL)]		0.9×V _{CC}	V _{CC}	1.1×V _C	0.9×V _{CC}	V _{CC}	1.1×V _C	0.9×V _C	V _{CC}	1.2×V _{CC}	V
V _{OD} (R)	Differential output voltage (Recessive)		-0.012		0.012	-0.014		0.017	-0.015		0.02	V
			-0.5		0.05	-0.5		0.225	-0.75		0.8	
V _{OC} (D)	Common-mode output voltage (Dominant)		2	2.3	3	2	2.3	3	2	2.3	3.1	V
V _{OC} (pp)	Peak-to-peak common-mode output voltage			0.3			0.3			0.3		
I _{IH}	High-level input current, TXD input	V _I at V _{CC}	-2		2	-3		3	-3		3	μA
I _{IL}	Low-level input current, TXD input	V _I at 0 V	-50		-10	-50		-10	-50		-10	μA
I _O (off)	Power-off TXD Leakage current	V _{CC} at 0 V, TXD at 5 V			1			180			600	μA
I _{OS} (ss)	Short-circuit steady-state output current	V _{CANH} = -12 V, CANL Open, See Figure 13	-120	-72		-120	-72		-130	-72		mA
		V _{CANH} = 12 V, CANL Open, See Figure 13		0.36	1		0.36	1		0.36	1.1	
		V _{CANL} = -12 V, CANH Open, See Figure 13	-1	-0.5		-1	-0.5		-1.1	-0.5		
		V _{CANL} = 12 V, CANH Open, See Figure 13		71	120		71	120		71	130	
C _O	Output capacitance	See Input capacitance to ground in RECEIVER ELECTRICAL CHARACTERISTICS .										

(1) All typical values are at 25°C with a 5-V supply.

DRIVER SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	T _J = -55°C to 125°C			T _J = -55°C to 175°C			T _J = -55°C to 210°C			UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
t _{PLH}	Propagation delay time, low-to-high-level output	STB at 0 V, See Figure 5	25	65	120	25	65	175	25	65	250	ns
t _{PHL}	Propagation delay time, high-to-low-level output		25	45	120	25	45	175	25	45	250	
t _{sk(p)}	Pulse skew (t _{PHL} – t _{PLH})		25			25			25			
t _r	Differential output signal rise time		25			25			25			
t _f	Differential output signal fall time		50			50			50			
t _{en}	Enable time from silent mode to dominant	See Figure 8	11			14.5			18			μs
t _{dom}	Dominant time-out	See Figure 11	300	450	700	300	450	700	300	450	700	μs

RECEIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER			TEST CONDITIONS	T _J = -55°C to 125°C			T _J = -55°C to 175°C			T _J = -55°C to 210°C			UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
V _{IT+}	Positive-going input threshold voltage	High-speed mode	STB at 0 V, See Table 3	800		900	800		900	800		900	mV
V _{IT–}	Negative-going input threshold voltage			500		650	500		650	500		650	
V _{hys}	Hysteresis voltage (V _{IT+} – V _{IT–})			100		125	70		125	70		125	
V _{IT}	Input threshold voltage	Standby mode	STB at V _{CC}	500		1150	500		1300	400		1350	
V _{OH}	High-level output voltage		I _O = –2 mA, See Figure 7	4	4.6		4	4.6		4	4.6		V
V _{OL}	Low-level output voltage		I _O = 2 mA, See Figure 7	0.2		0.4	0.2		0.5	0.2		0.55	V
I _{I(off)}	Power-off bus input current		CANH or CANL = 5 V, V _{CC} at 0 V, TXD at 0 V	5			15			30			μA
I _{O(off)}	Power-off RXD leakage current		V _{CC} at 0 V, RXD at 5 V	20			30			30			μA
C _I	Input capacitance to ground, (CANH or CANL)		TXD at 3 V, V _I = 0.4 sin (4E6πt) + 2.5 V	20			20			20			pF
C _{ID}	Differential input capacitance		TXD at 3 V, V _I = 0.4 sin (4E6πt)	10			10			10			pF
R _{ID}	Differential input resistance		TXD at 3 V, STD at 0 V	30		80	30		80	30		80	kΩ
R _{IN}	Input resistance, (CANH or CANL)		TXD at 3 V, STD at 0 V	15		30	15		30	15		30	
R _{I(m)}	Input resistance matching [1 – (R _{IN (CANH)} / R _{IN (CANL)})] x 100%		V _{CANH} = V _{CANL}	–3%	0%	3%	–5%	0%	5%	–12%	0%	12%	

RECEIVER SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	T _J = -55°C to 125°C			T _J = -55°C to 175°C			T _J = -55°C to 210°C			UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
t _{pLH}	Propagation delay time, low-to-high-level output	STB at 0 V, TXD at 3 V, See Figure 7	60	100	130	60	100	200	60	100	200	ns
t _{pHL}	Propagation delay time, high-to-low-level output		45	70	130	45	70	200	45	70	200	
t _r	Output signal rise time		8			8			8			
t _f	Output signal fall time		8			8			8			
t _{BUS}	Dominant time required on bus for wake-up from standby ⁽¹⁾	STB at V _{CC} Figure 12	0.7			1.0			1.45			μs

- (1) The device under test shall not signal a wake-up condition with dominant pulses shorter than t_{BUS} (min) and shall signal a wake-up condition with dominant pulses longer than t_{BUS} (max). Dominant pulses with a length between t_{BUS} (min) and t_{BUS} (max) may lead to a wake-up.

SPLIT-PIN CHARACTERISTICS

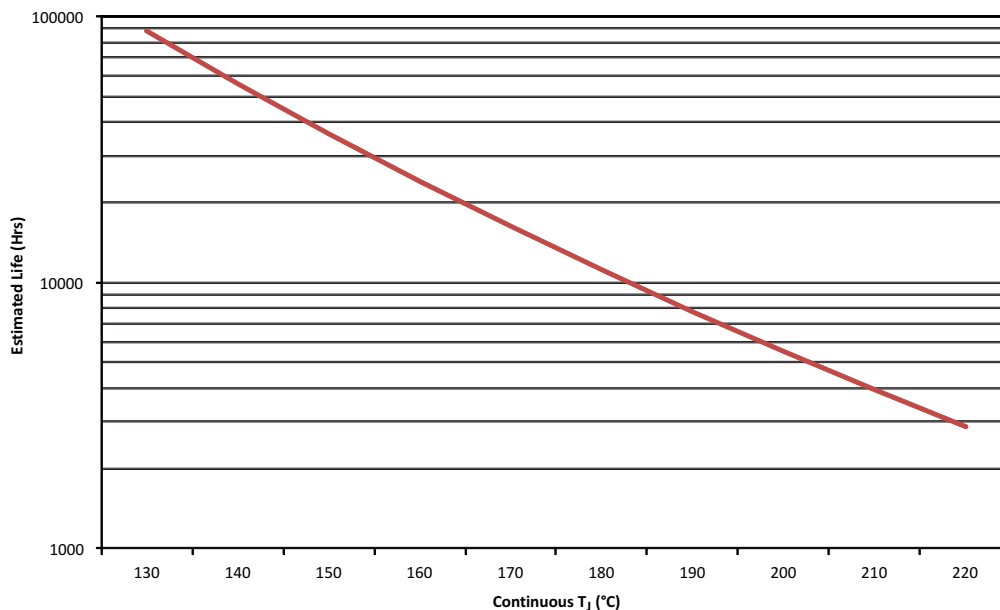
over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS	T _J = -55°C to 125°C			T _J = -55°C to 175°C			T _J = -55°C to 210°C			UNIT
			MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
V _O	Output voltage	–500 μA < I _O < 500 μA	0.3×V _{CC}	0.5×V _{CC}	0.7×V _{CC}	0.28×V _{CC}	0.5×V _{CC}	0.7×V _{CC}	0.28×V _C	0.5×V _C	0.7×V _{CC}	V
I _{O(st b)}	Standby mode leakage current	STB at 2 V, –12 V ≤ V _O ≤ 12 V	–5			–7			–15			μA

STB-PIN CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER	TEST CONDITIONS	T _J = -55°C to 125°C			T _J = -55°C to 175°C			T _J = -55°C to 210°C			UNIT
		MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
I _{IH}	High level input current	STB at 2 V	-10	0	-10	0	0	-10	0	0	μA
I _{IL}	Low level input current	STB at 0 V	-10	0	-10	0	0	-10	0	0	μA



- See datasheet for absolute maximum and minimum recommended operating conditions.
- Silicon operating life design goal is 10 years at 105°C junction temperature (does not include package interconnect life).
- The predicted operating lifetime vs. junction temperature is based on reliability modeling using electromigration as the dominant failure mechanism affecting device wear out for the specific device process and design characteristics.

Figure 1. SN65HVD1040-HT Operating Life Derating Chart

PARAMETER MEASUREMENT INFORMATION

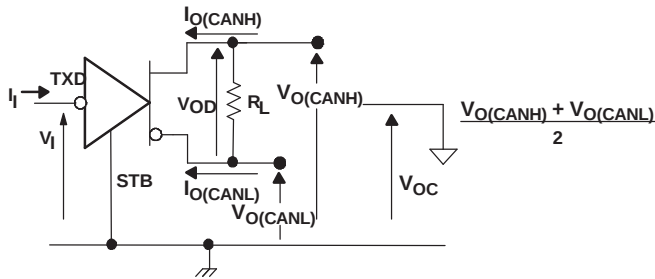


Figure 2. Driver Voltage, Current, and Test Definition

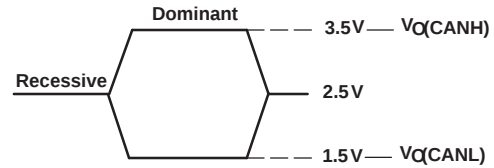


Figure 3. Bus Logic State Voltage Definitions

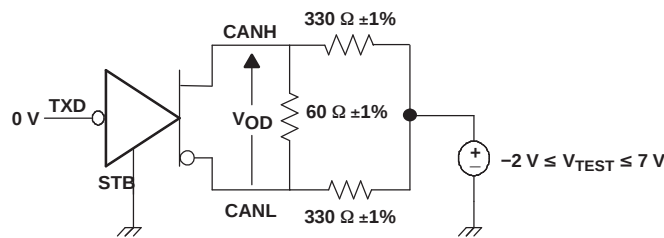


Figure 4. Driver V_{OD} Test Circuit

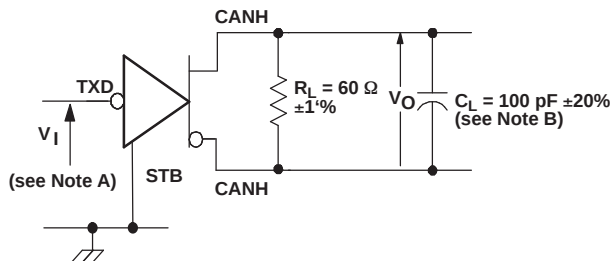


Figure 5. Driver Test Circuit and Voltage Waveforms

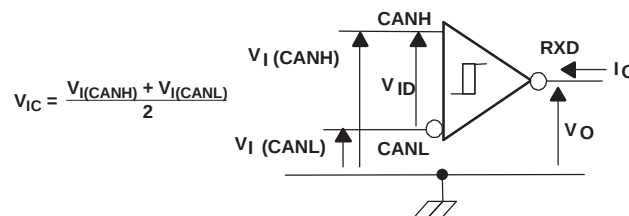
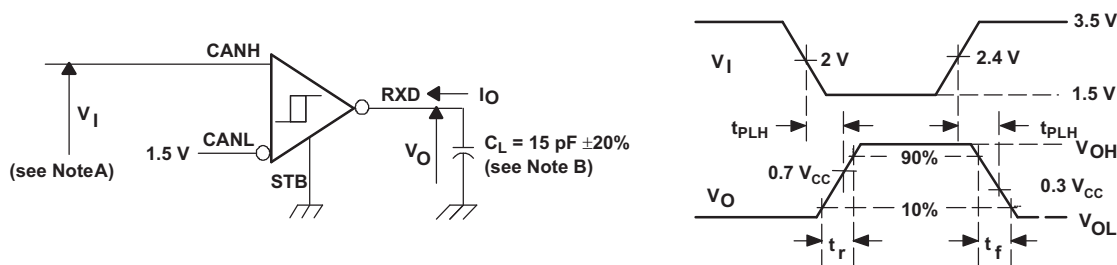


Figure 6. Receiver Voltage and Current Definitions

PARAMETER MEASUREMENT INFORMATION (continued)



- A. The input pulse is supplied by a generator having the following characteristics: PRR $\leq$ 125 kHz, 50% duty cycle, $t_r \leq$ 6 ns, $t_f \leq$ 6 ns, $Z_O = 50 \Omega$.
- B. C_L includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 7. Receiver Test Circuit and Voltage Waveforms

Table 3. Differential Input Voltage Threshold Test

INPUT			OUTPUT	
V_{CANH}	V_{CANL}	$ V_{ID} $	R	
-11.1 V	-12 V	900 mV	L	V_{OL}
12 V	11.1 V	900 mV	L	
-6 V	-12 V	6 V	L	
12 V	6 V	6 V	L	
-11.5 V	-12 V	500 mV	H	V_{OH}
12 V	11.5 V	500 mV	H	
-12 V	-6 V	6 V	H	
6 V	12 V	6 V	H	
Open	Open	X	H	

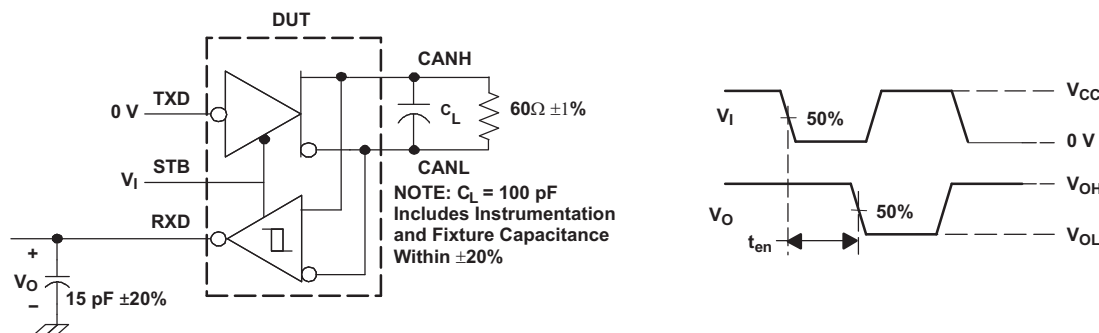
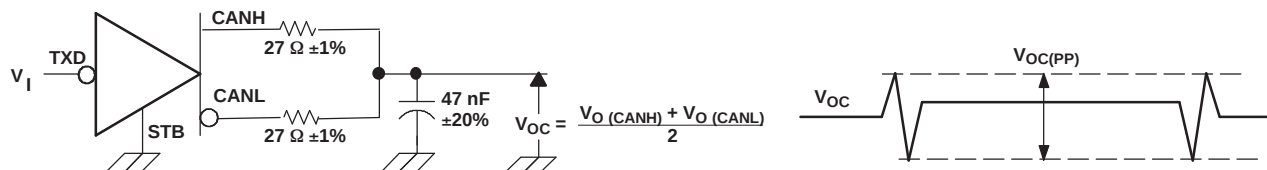
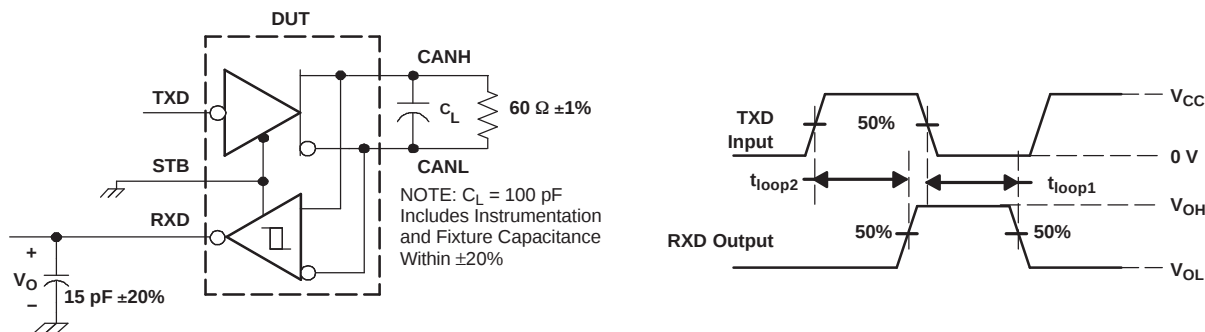


Figure 8. t_{en} Test Circuit and Voltage Waveforms



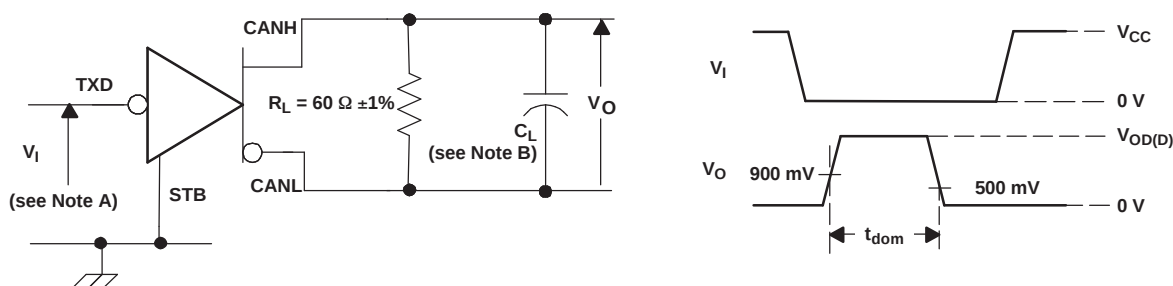
- A. All V_I input pulses are from 0 V to V_{CC} and supplied by a generator having the following characteristics: t_r or $t_f \leq$ 6 ns. Pulse Repetition Rate (PRR) = 125 kHz, 50% duty cycle.

Figure 9. Peak-to-Peak Common Mode Output Voltage Test and Waveform



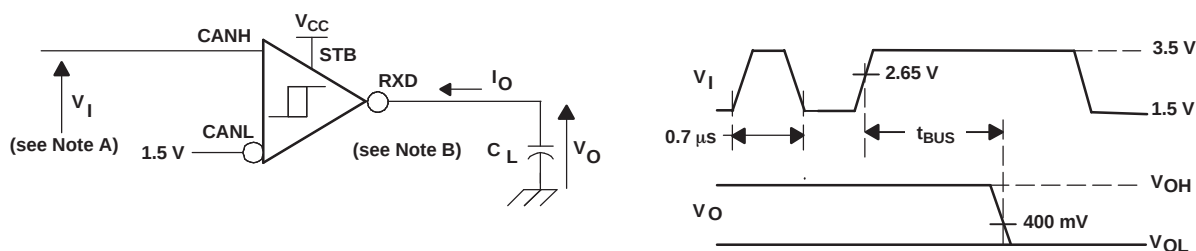
- A. All V_I input pulses are from 0 V to V_{CC} and supplied by a generator with the following characteristics: t_r or $t_f \leq 6$ ns. Pulse Repetition Rate (PRR) = 125 kHz, 50% duty cycle.

Figure 10. t_{loop} Test Circuit and Voltage Waveforms



- A. All V_i input pulses are from 0 V to V_{CC} and supplied by a generator with the following characteristics: t_r or $t_f \leq 6$ ns. Pulse Repetition Rate (PRR) = 500 Hz, 50% duty cycle.
- B. $C_1 = 100$ pF includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 11. Dominant Time-Out Test Circuit and Waveform



- A. For V_I bit width $\leq 0.7 \mu\text{s}$, $V_O = V_{OH}$. For V_I bit width $\geq 5 \mu\text{s}$, $V_O = V_{OL}$. V_I input pulses are supplied from a generator with the following characteristics; t_r or $t_f \leq 6 \text{ ns}$. Pulse Repetition Rate (PRR) = 50 Hz, 30% duty cycle.
- B. $C_L = 15 \text{ pF}$ includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 12. t_{BUS} Test Circuit and Waveform

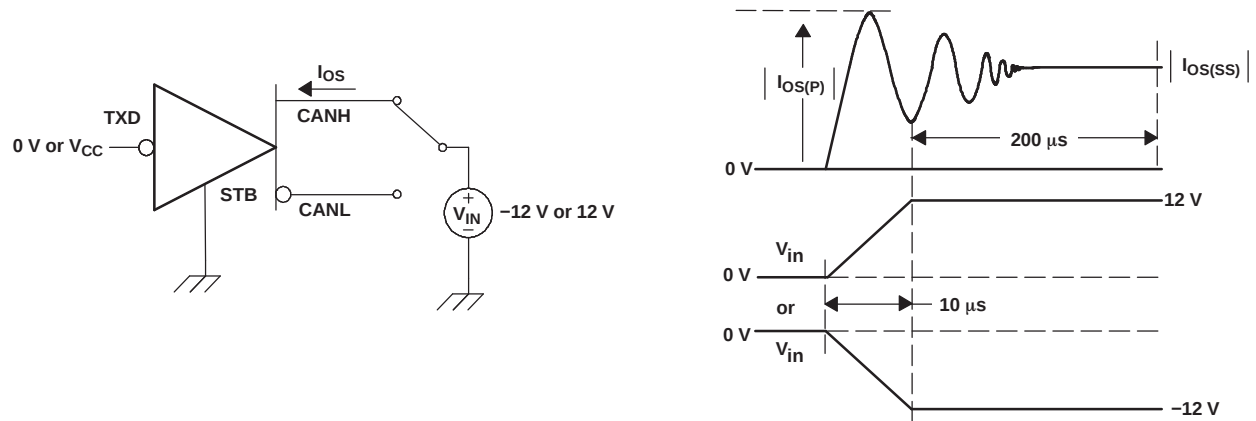


Figure 13. Driver Short-Circuit Current Test and Waveform

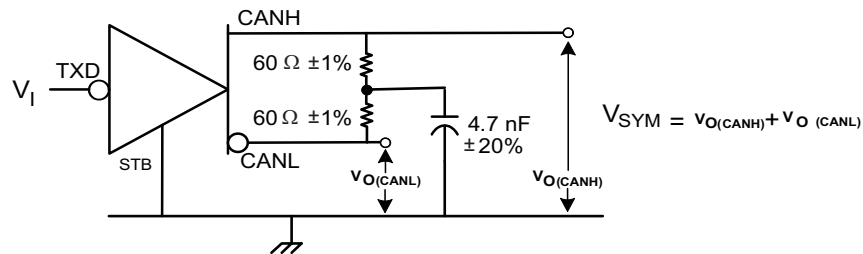


Figure 14. Driver Output Symmetry Test Circuit

DEVICE INFORMATION**Table 4. DRIVER FUNCTION TABLE⁽¹⁾**

INPUTS		OUTPUTS		BUS STATE
TXD	STB	CANH	CANL	
L	L	H	L	DOMINANT
H	L	Z	Z	RECESSIVE
Open	X	Z	Z	RECESSIVE
X	H or Open	Z	Z	RECESSIVE

(1) H = high level; L = low level; X = irrelevant; Z = high impedance

Table 5. RECEIVER FUNCTION TABLE⁽¹⁾

DIFFERENTIAL INPUTS $V_{ID} = \text{CANH} - \text{CANL}$	STB	OUTPUT RXD	BUS STATE
$V_{ID} \geq 0.9 \text{ V}$	L	L	DOMINANT
$V_{ID} \geq 1.15 \text{ V}$	H or Open	L	DOMINANT
$0.5 \text{ V} < V_{ID} < 0.9 \text{ V}$	X	?	?
$V_{ID} \leq 0.5 \text{ V}$	X	H	RECESSIVE
Open	X	H	RECESSIVE

(1) H = high level; L = low level; X = irrelevant; ? = indeterminate; Z = high impedance

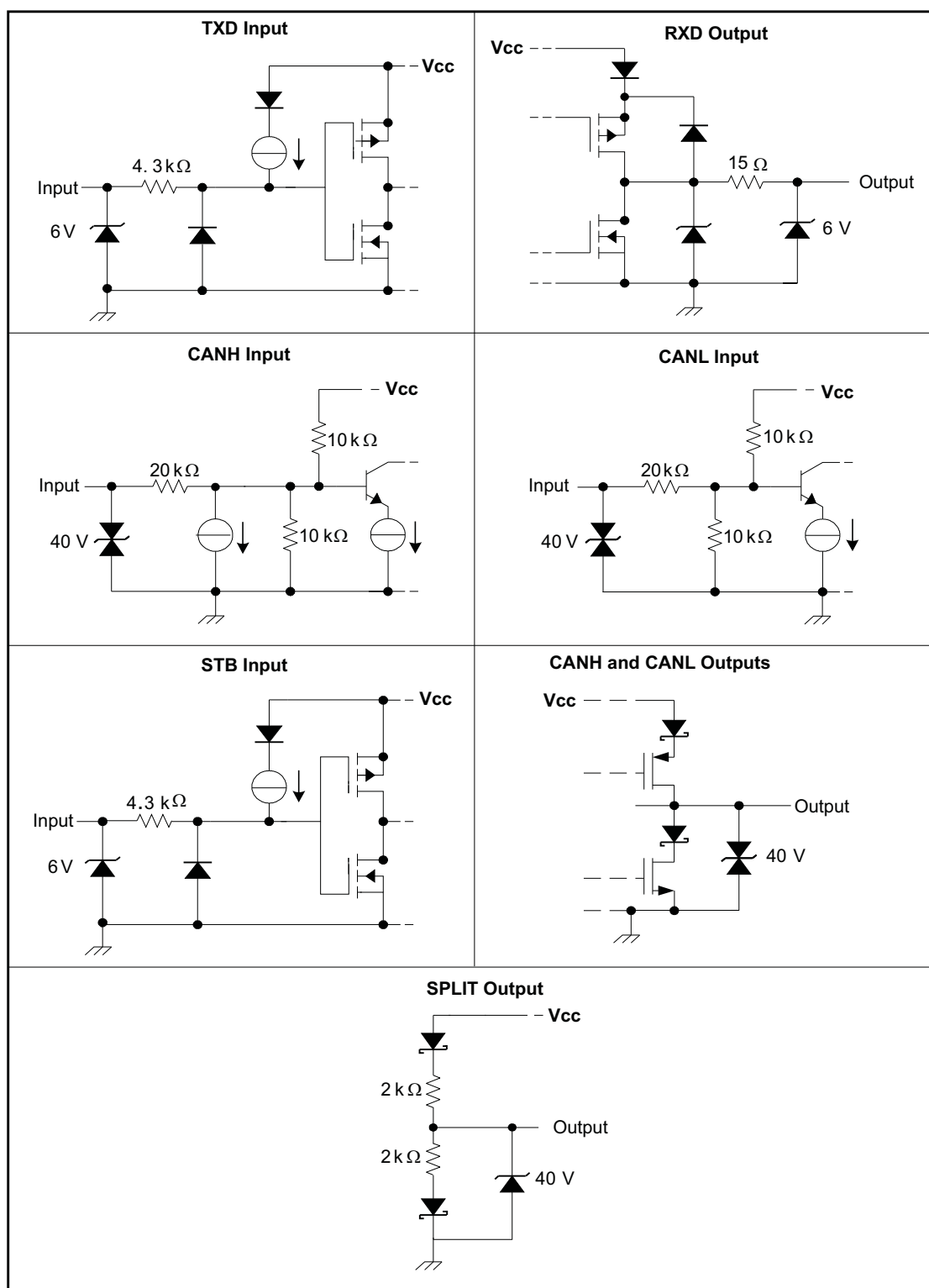
DEVICE INFORMATION

Table 6. Parametric Cross Reference With the TJA1040

TJA1040⁽¹⁾	PARAMETER	HVD10xx
TJA1040 DRIVER SECTION		
V_{IH}	High-level input voltage	Recommended V_{IH}
V_{IL}	Low-level input voltage	Recommended V_{IL}
I_{IH}	High-level input current	Driver I_{IH}
I_{IL}	Low-level input current	Driver I_{IL}
TJA1040 BUS SECTION		
$V_{th(dif)}$	Differential input voltage	Receiver V_{IT} and recommended V_{ID}
$V_{hys(dif)}$	Differential input hysteresis	Receiver V_{hys}
$V_{O(dom)}$	Dominant output voltage	Driver $V_{O(D)}$
$V_{O(reces)}$	Recessive output voltage	Driver $V_{O(R)}$
$V_{I(dif)(th)}$	Differential input voltage	Receiver V_{IT} and recommended V_{ID}
$V_{O(dif0(bus))}$	Differential bus voltage	Driver $V_{OD(D)}$ and $V_{OD(R)}$
I_{LI}	Power-off bus input current	Receiver $I_{I(off)}$
$I_{O(SC)}$	Short-circuit output current	Driver $I_{OS(SS)}$
$R_{I(cm)}$	CANH, CANL input resistance	Receiver R_{IN}
$R_{I(def)}$	Differential input resistance	Receiver R_{ID}
$R_{I(cm)} (m)$	Input resistance matching	Receiver $R_{I(m)}$
$C_{I(cm)}$	Input capacitance to ground	Receiver C_I
$C_{I(dif)}$	Differential input capacitance	Receiver C_{ID}
TJA1040 RECEIVER SECTION		
I_{OH}	High-level output current	Recommended I_{OH}
I_{OL}	Low-level output current	Recommended I_{OL}
TJA1040 SPLIT PIN SECTION		
V_O	Reference output voltage	V_O
TJA1040 TIMING SECTION		
$t_d(TXD-BUSon)$	Delay TXD to bus active	Driver t_{PLH}
$t_d(TXD-BUSoff)$	Delay TXD to bus inactive	Driver t_{PHL}
$t_d(BUSon-RXD)$	Delay bus active to RXD	Receiver t_{PHL}
$t_d(BUSoff-RXD)$	Delay bus inactive to RXD	Receiver t_{PLH}
$t_{PD}(TXD-RXD)$	Prop delay TXD to RXD	Device t_{LOOP1} and t_{LOOP2}
$t_d(stb-norm)$	Enable time from standby to dominant	Driver t_{en}
TJA1040 STB PIN SECTION		
V_{IH}	High-level input voltage	Recommended V_{IH}
V_{IL}	Low-level input voltage	Recommended V_{IL}
I_{IH}	High-level input current	I_{IH}
I_{IL}	Low-level input current	I_{IL}

(1) From TJA1040 Product Specification, Philips Semiconductors, 2003 February 19.

Equivalent Input and Output Schematic Diagrams



TYPICAL CHARACTERISTICS

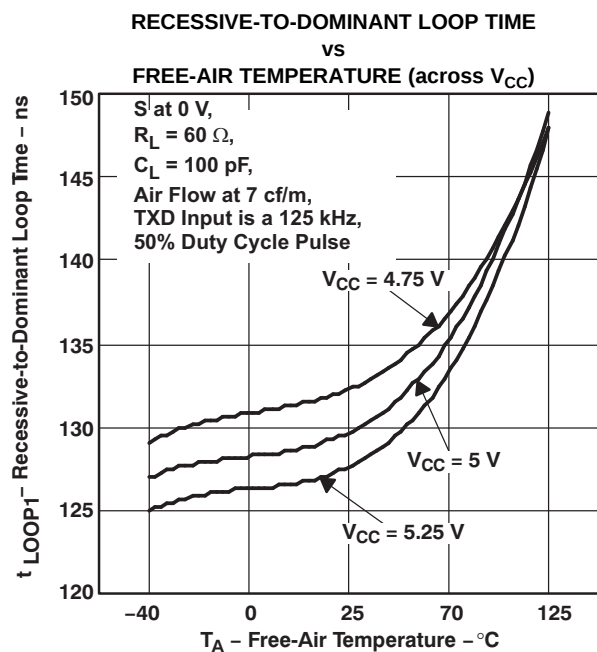


Figure 15.

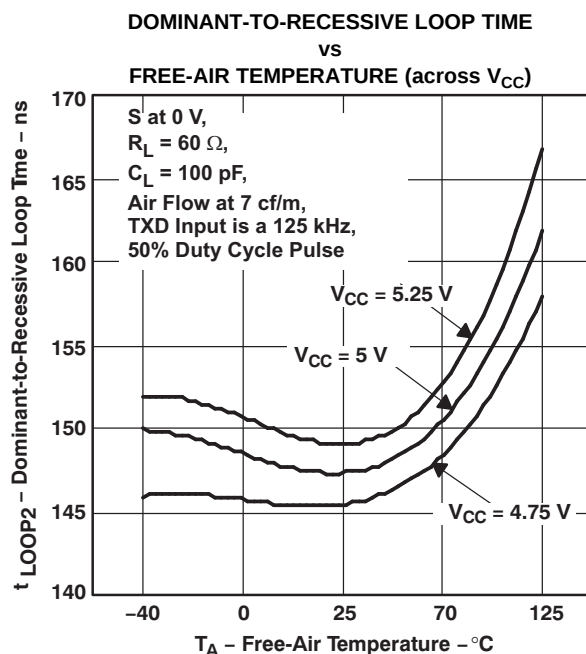


Figure 16.

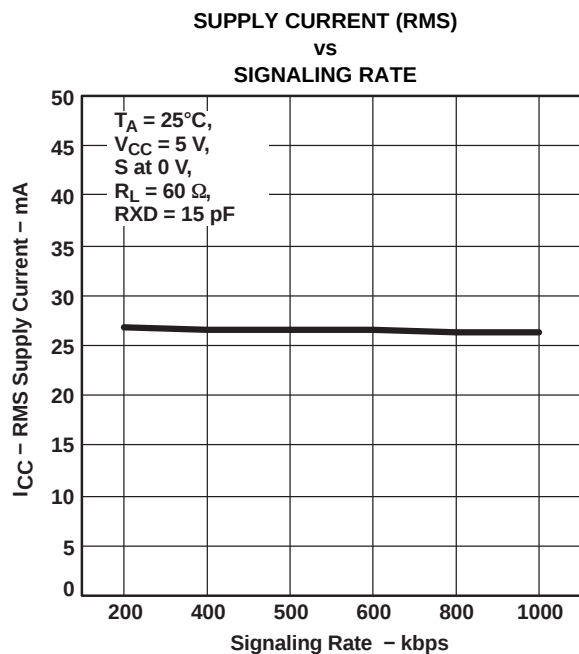


Figure 17.

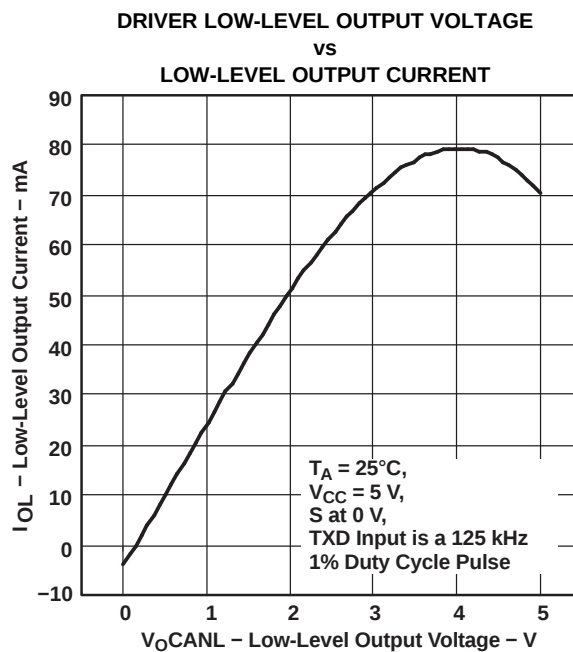


Figure 18.

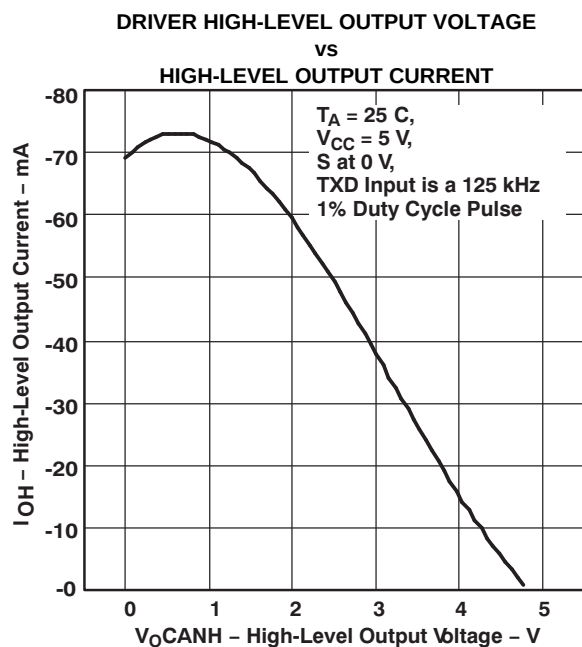
TYPICAL CHARACTERISTICS (continued)

Figure 19.

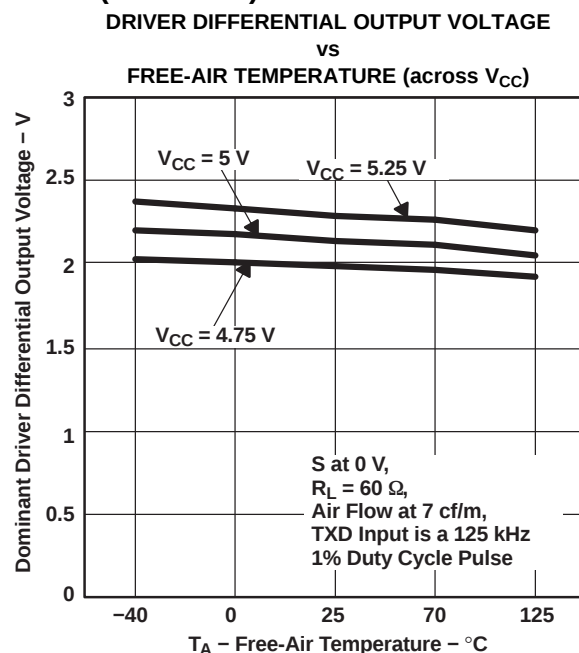


Figure 20.

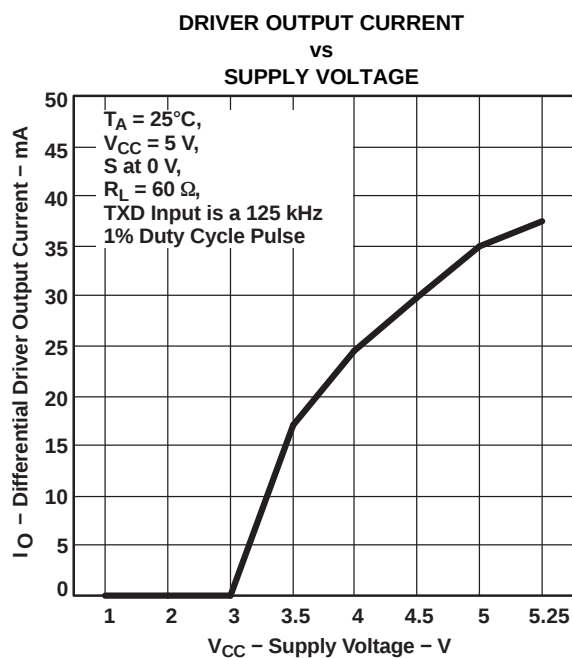


Figure 21.

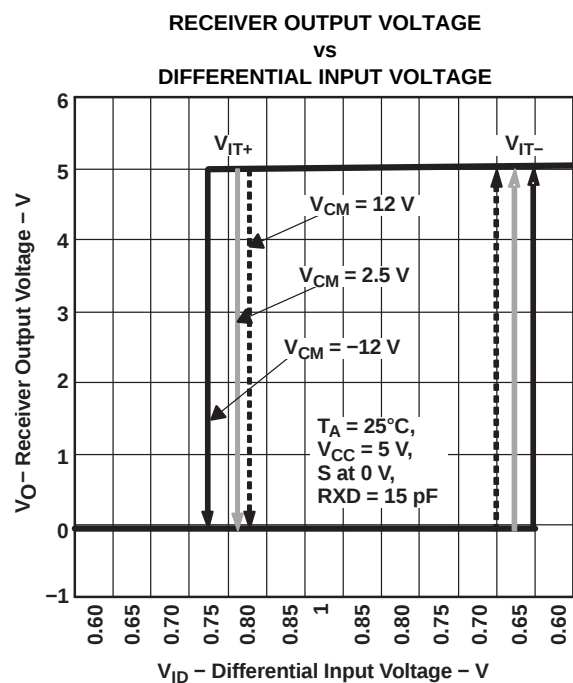


Figure 22.

TYPICAL CHARACTERISTICS (continued)

**TYPICAL ELECTROMAGNETIC EMISSIONS
UP TO 50 MHz (Peak Amplitude)**

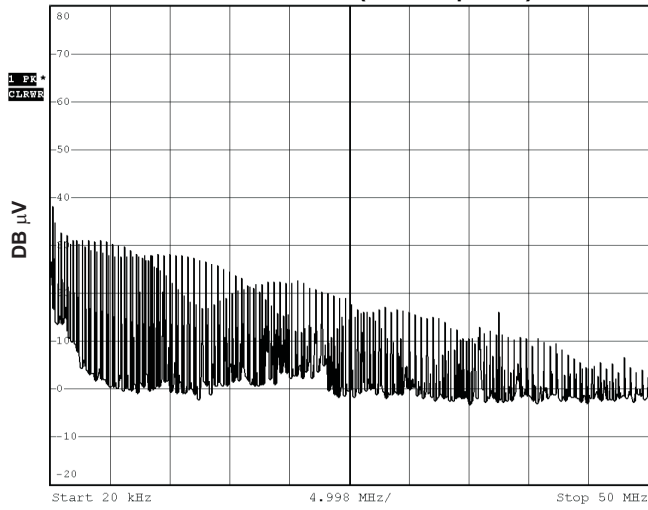


Figure 23. Frequency Spectrum of Common-Mode Emissions

**TYPICAL ELECTROMAGNETIC
IMMUNITY PERFORMANCE**

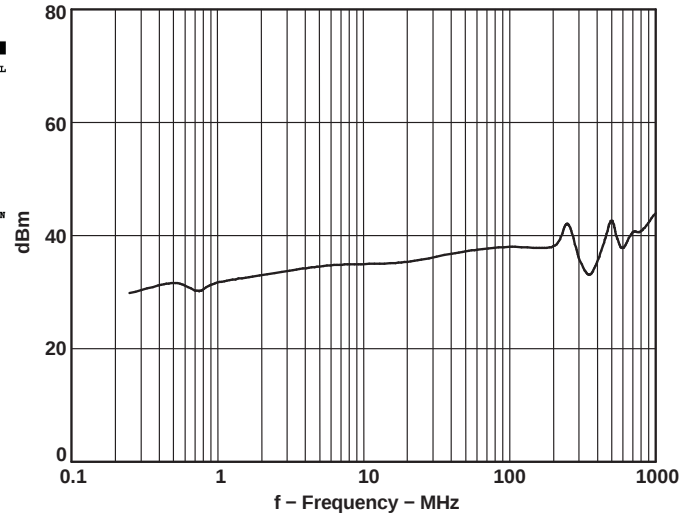


Figure 24. Direct Power Injection (DPI) Response vs Frequency

APPLICATION INFORMATION

CAN Basics

The basics of arbitration require that the receiver at the sending node designate the first bit as dominant or recessive after the initial wave of the first bit of a message travels to the most remote node on a network and back again. Typically, this “sample” is made at 75% of the bit width, and within this limitation, the maximum allowable signal distortion in a CAN network is determined by network electrical parameters.

Factors to be considered in network design include the approximately 5 ns/m propagation delay of typical twisted-pair bus cable; signal amplitude loss due to the loss mechanisms of the cable; and the number, length, and spacing of drop-lines (stubs) on a network. Under strict analysis, variations among the different oscillators in a system also need to be accounted for with adjustments in signaling rate and stub and bus length. [Table 7](#) lists the maximum signaling rates achieved with the SN65HVD1040 with several bus lengths of category 5, shielded twisted pair (CAT 5 STP) cable.

Table 7. Maximum Signaling Rates for Various Cable Lengths

Bus Length (m)	Signaling Rate (kbps)
30	1000
100	500
250	250
500	125
1000	62.5

The ISO 11898 Standard specifies a maximum bus length of 40 m and maximum stub length of 0.3 m with a maximum of 30 nodes. However, with careful design, users can have longer cables, longer stub lengths, and many more nodes to a bus. (Note: Non-standard application may come with a trade-off in signaling rate.) A large number of nodes requires a transceiver with high input impedance such as the HVD1040.

The Standard specifies the interconnect to be a single twisted-pair cable (shielded or unshielded) with 120 Ω characteristic impedance (Z_0). Resistors equal to the characteristic impedance of the line terminate both ends of the cable to prevent signal reflections. Unterminated drop-lines connect nodes to the bus and should be kept as short as possible to minimize signal reflections.

Connectors, while not specified by the standard should have as little effect as possible on standard operating parameters such as capacitive loading. Although unshielded cable is used in many applications, data transmission circuits employing CAN transceivers are usually used in applications requiring a rugged interconnection with a wide common-mode voltage range. Therefore, shielded cable is recommended in these electronically harsh environments, and when coupled with the Standard's –2-V to 7-V common-mode range of tolerable ground noise, helps to ensure data integrity. The HVD1040 enhances the Standard's insurance of data integrity with an extended –12 V to 12 V range of common-mode operation.

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
SN65HVD1040HD	Active	Production	SOIC (D) 8	75 TUBE	Yes	NIPDAU	Level-4-260C-72 HR	-55 to 175	H1040
SN65HVD1040HD.A	Active	Production	SOIC (D) 8	75 TUBE	Yes	NIPDAU	Level-4-260C-72 HR	-55 to 175	H1040
SN65HVD1040HDG4	Active	Production	SOIC (D) 8	75 TUBE	Yes	NIPDAU	Level-4-260C-72 HR	-55 to 210	H1040
SN65HVD1040HDG4.A	Active	Production	SOIC (D) 8	75 TUBE	Yes	NIPDAU	Level-4-260C-72 HR	-55 to 210	H1040
SN65HVD1040SHKQ	Active	Production	CFP (HKQ) 8	25 TUBE	Yes	AU	N/A for Pkg Type	-55 to 210	HVD1040S HKQ
SN65HVD1040SHKQ.A	Active	Production	CFP (HKQ) 8	25 TUBE	Yes	AU	N/A for Pkg Type	-55 to 210	HVD1040S HKQ
SN65HVD1040SKGD3	Active	Production	XCEPT (KGD) 0	210 TUBE	Yes	Call TI	N/A for Pkg Type	-55 to 210	
SN65HVD1040SKGD3.A	Active	Production	XCEPT (KGD) 0	210 TUBE	Yes	Call TI	N/A for Pkg Type	-55 to 210	

⁽¹⁾ **Status:** For more details on status, see our [product life cycle](#).

⁽²⁾ **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

⁽⁴⁾ **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "-" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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OTHER QUALIFIED VERSIONS OF SN65HVD1040-HT :

- Catalog : [SN65HVD1040](#)
- Automotive : [SN65HVD1040-Q1](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product
- Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

TUBE



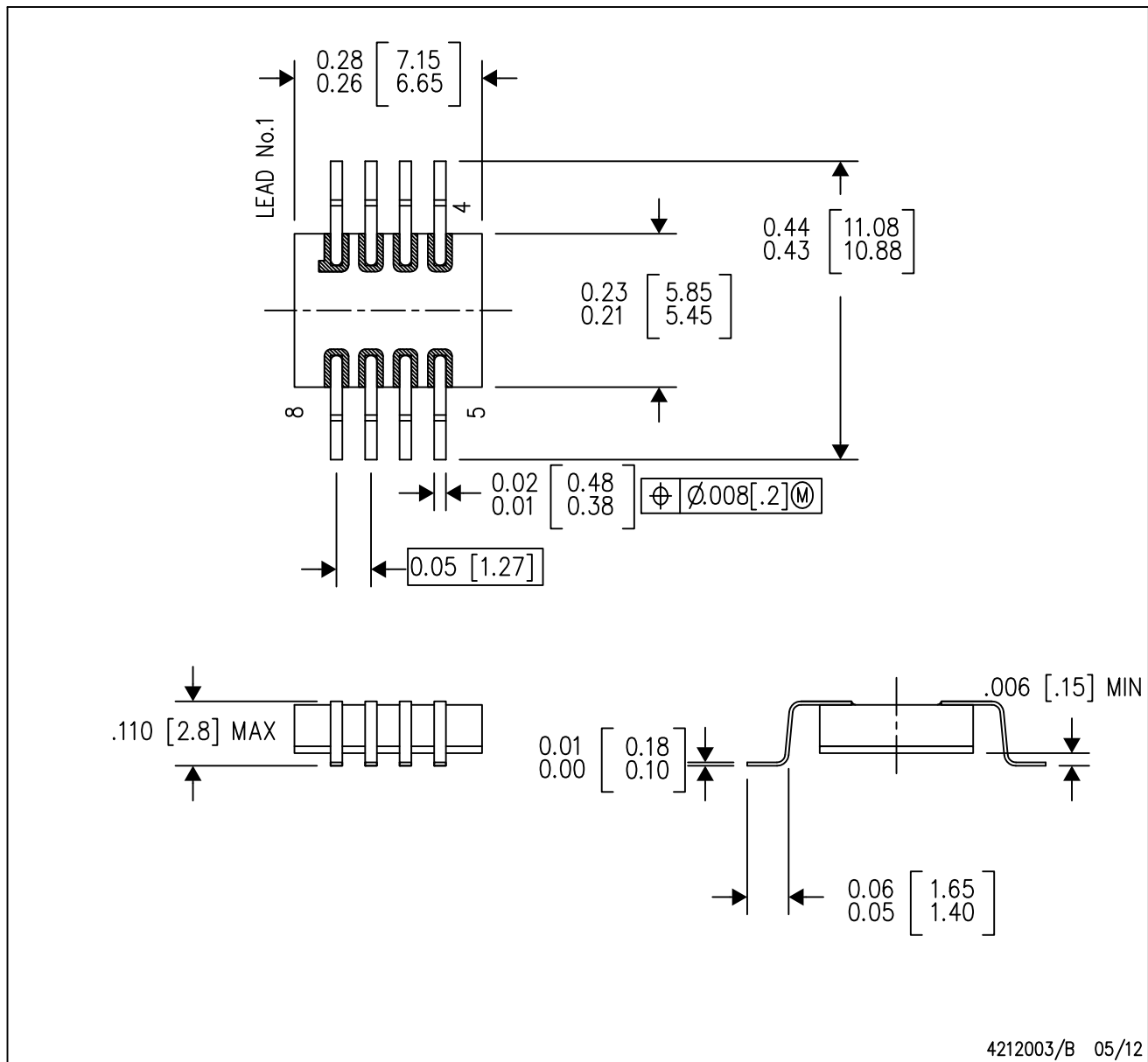
*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (μm)	B (mm)
SN65HVD1040HD	D	SOIC	8	75	505.46	6.76	3810	4
SN65HVD1040HD.A	D	SOIC	8	75	505.46	6.76	3810	4
SN65HVD1040HDG4	D	SOIC	8	75	505.46	6.76	3810	4
SN65HVD1040HDG4.A	D	SOIC	8	75	505.46	6.76	3810	4
SN65HVD1040SHKQ	HKQ	CFP	8	25	506.98	26.16	6220	NA
SN65HVD1040SHKQ.A	HKQ	CFP	8	25	506.98	26.16	6220	NA

MECHANICAL DATA

HKQ (R-CDFP-G8)

CERAMIC GULL WING



4212003/B 05/12

- NOTES:
- A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice.
 - C. This package can be hermetically sealed with a metal lid.
 - D. The terminals will be gold plated.
 - E. Lid is not connected to any lead.

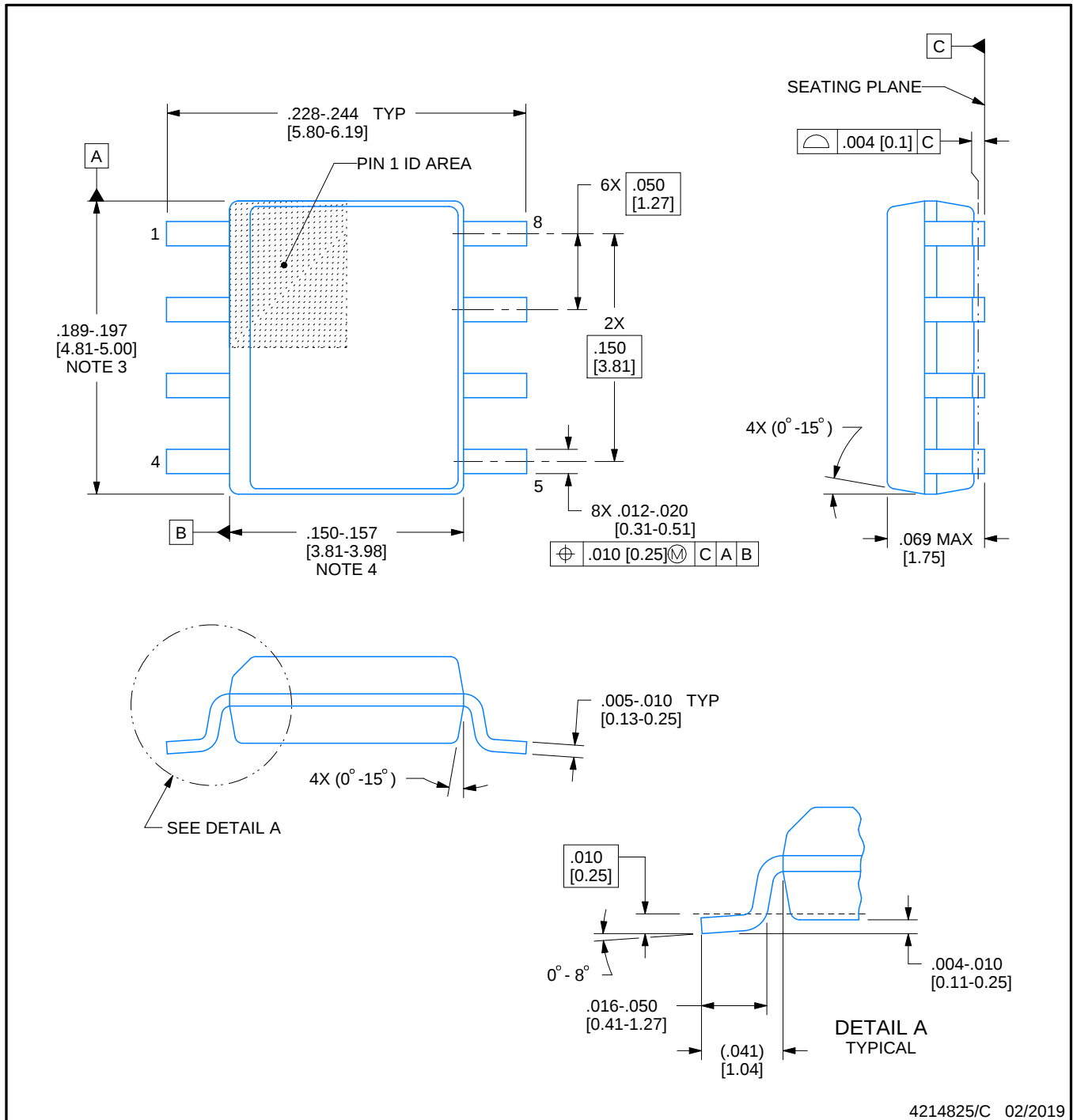


D0008A

PACKAGE OUTLINE

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



4214825/C 02/2019

NOTES:

1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
4. This dimension does not include interlead flash.
5. Reference JEDEC registration MS-012, variation AA.

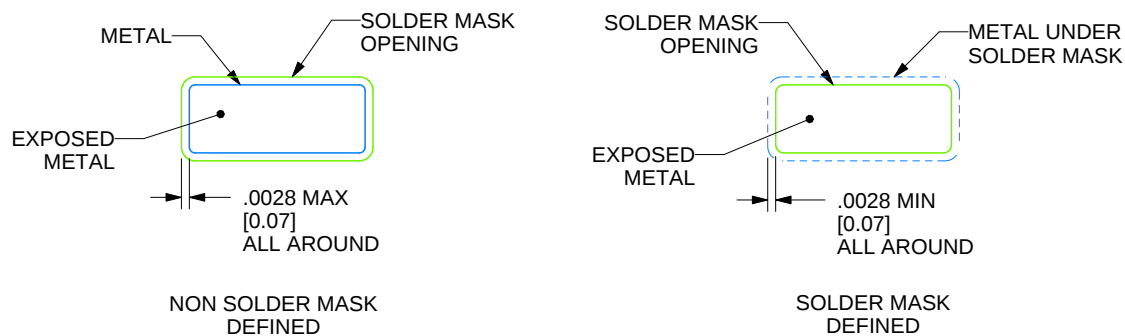
D0008A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:8X



SOLDER MASK DETAILS

4214825/C 02/2019

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

D0008A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



SOLDER PASTE EXAMPLE
BASED ON .005 INCH [0.125 MM] THICK STENCIL
SCALE:8X

4214825/C 02/2019

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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最后更新日期：2025 年 10 月